

a[.] the focal length is between forty and forty-one millimeters over a range of wavelengths of at least two-hundred to seven-hundred nanometers;

b[.] the focal length varies by less than five (5%) percent over a range of wavelengths of between two-hundred and five-hundred nanometers; and

c[.] the spot diameter at the focal length is less than seventy-five microns over a range of wavelengths of at least two-hundred to seven-hundred nanometers.

74. CURRENTLY AMENDED. A system as in Claim 47 which is an ellipsometer or polarimeter system in which the input and output lenses are part of a system sequentially comprising:

a[.] a source of a spectroscopic beam
electromagnetic
radiation;

b[.] a polarizer element;

in either order elements c[.] and d[.]:

c[.] optionally a compensator element;

d[.] said input lens;

e[.] a material system;

in either order elements f[.] and g[.]:

f[.] said output lens;

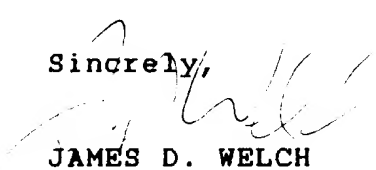
g[.]) optionally a compensator element;

h[.]) an analyzer element; and

i[.]) a detector System.

It is now believed that the Application is in order for Allowance, and the Examiner is respectfully requested to Allow the Pending New Claims 47 - 76. Should problems remain please contact Attorney Welch. Applicant is receptive to suggestions of and Amendments by the Examiner.

Sincerely,



JAMES D. WELCH

JW/hs